ZeeScope

Compact 3D Digital Microscope

▲ PhaseView

PhaseView*

150

10

Applications:

3D Image documentation Z-Stacking Extended depth of field 3D Shape Image fusion Roughness Z Depth measurement Surface Metrology

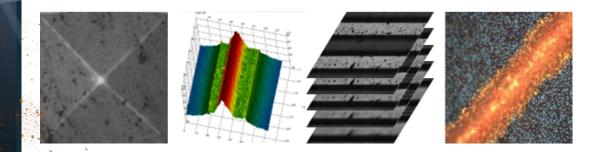
Labs & Field Inspection :

Metal Tooling Forensics Printing Archeology Education Electronics Semiconductor Museum Automotive Aeropace Geology



Compact 3D Digital Microscope

- High Resolution Digital Microscopy
- Accurate Z Depth Measurement
- Fast 3D Acquisition and Analysis
- Automatic Depth Composition
- 3D Surface Metrology



PORTABLE 3D DIGITAL MICROSCOPE The Easiest Way To 3D Imaging

- No Moving Parts
- All-In-One Device
- Maintenance Free
- No Costly Accessories
- User Friendly Software





ZeeScope Head



ZeeScope Control Unit



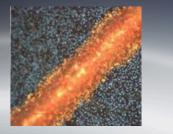
Optional Lithium battery for Field autonomy





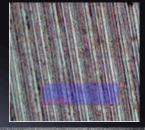
High Resolution Digital Microscope Camera

Megapixel CCD · 2D Measurements · Graphics Overlay · Report





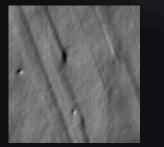


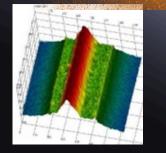


ZeeScope provides sharp & crisp digital images in real time, featuring all necessary tools for digital image documentation in high resolution.

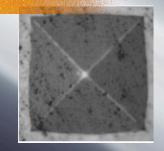
Multiple Imaging Capabilitie

AutoFocus • Depth Measurement • Z-Stacking • Extended Depth of Field • 3D Reconstruction





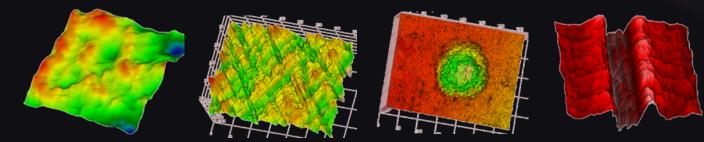




Thanks to its integrated ZeeScan module, the 3D Digital Microscope performs all critical tasks in material microscopy while using a standard upright or inverted microscope.

3D Surface Metrology

Surface Shape • Roughness • Waviness • Step Height



ZeeScope is the quickest and easiest way for precise surface topography measurements compared to complex, bulky and expensive systems.



Applications



Light Portable Microscope For Field Inspection

- On site Quality
 Control
- Field Inspection
- Maintenance

Applications

Surface Metrology 3D Shape Roughness Corrosion analysis Z Depth Digs , scratches QC Surface inspection



Accurate 3D Microscope For Labs & Shop Floor

- Shop Floor Rapid Testing
- R&D Labs
- QC Laboratories

Industries

Metal Tooling Printed Board Medical Automotive Aerospace Semiconductor Solar Cells Electrics Food Packaging Wood Flooring Adhesive Beads Weld Seams



3D Industrial Quality Control

- Manufacturing Quality Control
- Shop Floor
 Diagnostic Tool
- Machine Vision
 3D Camera
- Automated Optical Inspection

Smart 3D vision No Moving Parts All-In-One Device Maintenance Free Affordable Solution Easy Implementation



GetPhase[®] GUI software (included) is compatible with Windows 8, 7, XP & Vista. GetPhase[®] provides comprehensive tools from automatic acquisition to 2D / 3D image analvsis. documentation and reports. Including Z -stacking, Z height measurement, Image fusion (Extended Depth of Field), 3D reconstruction and measurements, multiple display modes: DIC, Phase, brightfield, darkfield, surface and profile roughness, step height measurements.

Software

API / SDK (optional) for controlling ZeeScope acquisition, routines for Z-stack, 3D reconstruction, EDF, DIC, Phase, and 3D surface analysis.

Acquisition & Processing

2D / 3D Acquisition Wizard
 Auto Focus & Exposure
 Region-of-Interest

 Navigator
 Stitching
 Macro Recording

2D/3D Display & Analysis

BF, DF, Ph, DIC, 3D views
Text & Graphics overlay
2D / 3D measurements
Image fusion (EDF)
Roughness ISO standards
Step Height Measurements

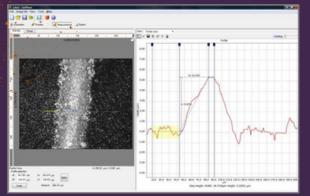
Image Data Export & Report

-Project Archiving -3D Data in Excel Format -3D Data for 3rd Party Software -Report Editor -HTML Compatible Presentation

Powerful Imaging Tool

Z-stacking of high resolution images can be automatically achieved providing image fusion image (Extended depth of Fiel image, Z depth measurement or 3D reconstruction. In addition, GetPhase provides 2D measurements and image documentation tools.

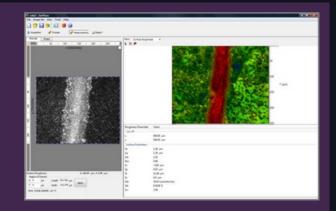
- Reveals finest structure details without specialized optics
- On click Image documentation with
 multiple views
- Automatic image fusion (Extended Depth of Field)
- 2D measurements & report



Fast & Accurate 3D Surface Metrology

ZeeScan with GetPhase performs 3D acquisition and analysis in a remarkable fast and easy way. Non contact optical surface profiling is highly repeatable.

- 3D surface analysis in micrometer and nanometer range
- Measurement capabilities from smooth to rough surfaces
- ISO Roughness and step heights measurements
- High throughput thanks to fast acquisition & processing time



ZeeScope Smart Hardware Architecture

Smart Hardware ZeeScope is an all-in one 3D digital microscope controlled by PC with a single USB2 connection and integrating the proprietary PhaseView ZeeScan optical assembly . Accurate calibration is achieved using an automated procedure and stored in an internal memory to prevent any losses.

	ZeeScope 100	ZeeScope 150	SeeScope 200
Camera	½"CMOS 1280 x 1024 5.2µm square pixels 30fps@full resolution	1/1.8"CCD 1616 x 1216 4.40 square pixels 12fps@full resolution	1/2"CCD 2560 x 1920 2.20 square pixels 6fps@full resolution
Light source	Built-in coaxial LED light source		
Objectives	Interchangeable objectives (Finite - Infinite type) adapter provided for threads RMS and M25/0.75		
Dimensions & weight ZeeScope Head Control unit	225(H) x 40 (W) x 55(D) mm, 425g 40(H) 158(W) 150(D) mm, 150g		
Power Supply	110/220V AC		
PC Interface	USB 2.0		

3D Measurement Performance

Z range and resolution are objective and c-mount coupler magnification dependant. The table here under gives typical performance for standard objective magnification. For any other magnification, the following formulas can be applied :

- Z Range = 60mm / (G_Obj)²
- Z Resolution = Objective Depth Of Field /4
- **G_Obg = Objective magnification**

Objective Mag / NA	Z Range (µm)	Z Resolution (µm)
5X / 0.10	2 400	18,5
10X / 0.25	600	3
20X / 0.45	150	1
50X / 0.8	24	0,25

Z accuracy: 1% Z Repeatability: 0.35% Max slope: 90° XY Spatial resolution determined by camera resolution and objective magnification

Roughness Measurement

12 analysis parameters are provided in total, including the frequently-used Ra (Sa), Rq (Sq), Rz (Sz), parameters. Parameters conform to ISO 4287, 25178 DIN 4768

Measuring range: Ra, Rq: 0.01-500µm Measuring accuracy: ≤±10% Repeatability: ≤6%





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